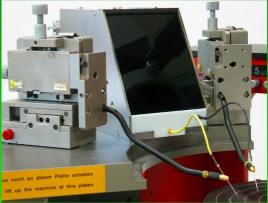
High Voltage Wafer HBM/HMM Tester

HED-W5000M-HV (Max30kV)

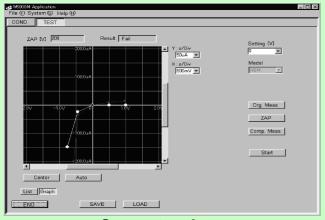


HBM/HMM testing of packages and wafers is now possible!

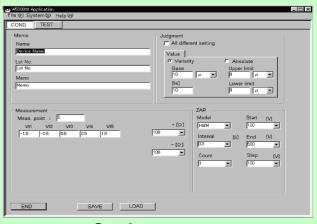


- 1. Performs HBM(Human Body Model) zap (15kV)
- 2. Performs HMM(Human Metal Model) zap (30kV)
- 3. The real device's ESD waveform can be displayed
- 4. Performs automatic destructive evaluation of V/I measurement after zap for excellent cost performance.
- 5. Connects with two needles to any device such as wafers.
- Zap unit can be installed on the customer's manual PROBER.
- 7. Clear correlation of the test results of a package device.

Operation screen



Curve tracing



Setting screen

Specification

Model HED-W5000M-HV

Waveform HBM:Max 15kV,

HMM (IEC 61000-4-2) Max 30kV, MM:4kV

Charging voltage 10 to +/-30kV

Charging resolution 10V

Charging accuracy 5 %+/-5V ZAP count 1 to 99

Interval time 0.3 to 9.9 S

Test pins Manual positioning

Physical (main unit) 325(W) / 500(D) / 200(H) 15 Kg (PC no contained)

Physical (Zap unit) 74(W) / 105(D) / 138(H) 1 Kg

Curve Tracing voltage 0 to +/- 40V

CurveTracing Resolution 0.1V

Curve Tracing current Max 100mA

Detection resistance 10,100,1k,10k,100k,1M ohm

Measurement range 10nA,100nA,1uA,10uA,100uA,1mA,10mA,100mA

Curve Tracing Accuracy 1% +/- (1/500 F.S +/- 10nA)

Measurement point Max 20

Judgment Relatively and Absolute value

Control RS-232C Operation Windows

(HANWA)

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